Special Issue

Advanced Remote Sensing Imaging for Environmental Sciences

Message from the Guest Editors

Remote sensing imaging is an active source of spatial information which has been proven to be effective in measuring and monitoring the environment. Conversely, hyperspectral remote sensing imaging combines imaging technology with spectral detection technology, which is characterized by integrating image information of the sample with spectral information. However, the ability of existing methods to identify features is significantly affected by the high data dimensionality and massive information redundancy of hyperspectral remote sensing data. To solve the above problems, we must develop a variety of advanced hyperspectral remote sensing imaging analysis techniques for use in environmental monitoring systems. This Special Issue encourages scholars and experts to submit works that systematically explore various advanced remote sensing imaging methods for application to environmental science to provide new ideas and references for exploring and addressing pressing environmental science issues. We welcome both original research and review articles.

Guest Editors

Dr. Weiwei Cai

1. Graduate School, Northern Arizona University, Flagstaff, AZ 86011, USA
2. School of Artificial Intelligence and Computer Science, Jiangnan University, Wuxi 214122, China

Dr. Jianlei Kong

1. National Engineering Research Center for Agricultural Product Quality Safety and Traceability Technology and Application, Beijing 100048, China
2. School of Computer and Artificial Intelligence, Beijing Technology and Business University, Beijing 100048, China

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Applied Sciences
Editorial Office
MDPI, Grosspeteranlage 5
4052 Basel, Switzerland
Tel: +41 61 683 77 34
applsci@mdpi.com

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As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

Editor-in-Chief

Prof. Dr. Giulio Nicola Cerullo
Dipartimento di Fisica, Politecnico di Milano, Piazza L. da Vinci 32, 20133 Milano, Italy

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